

<b>Notice of References Cited</b>	Application/Control No. 10/719,518	Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Fayyaz Alam	Art Unit 2618	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0032039 A1	03-2002	Kimata, Yusuke	455/556
*	B	US-2002/0065071 A1	05-2002	Hunzinger, Jason F.	455/421
*	C	US-2002/0081971 A1	06-2002	Travostino, Franco	455/41
*	D	US-2002/0111138 A1	08-2002	Park, Seok-Hyo	455/41
*	E	US-2002/0147003 A1	10-2002	Tada et al.	455/412
*	F	US-2003/0027526 A1	02-2003	Hillyard, Jason	455/41
*	G	US-2003/0078002 A1	04-2003	Sanjeev et al.	455/41
*	H	US-2003/0224757 A1	12-2003	Dyck et al.	455/411
*	I	US-2004/0198226 A1	10-2004	Watson et al.	455/041.2
*	J	US-7,046,961 B2	05-2006	Park, Seok-Hyo	455/41.2
*	K	US-7,065,354 B2	06-2006	Park et al.	455/426.1
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.